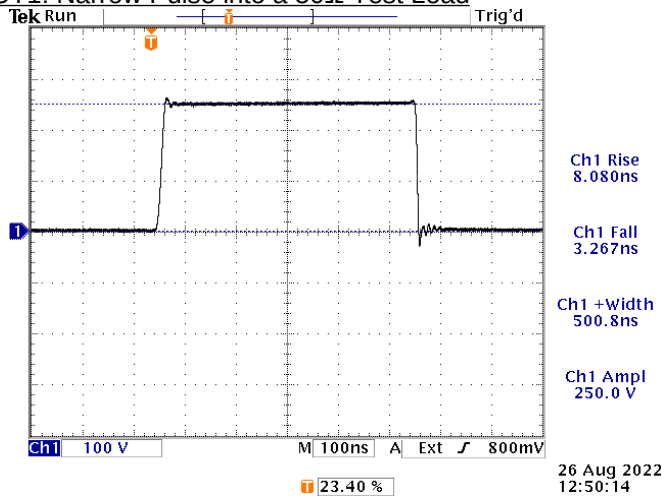




PERFORMANCE CHECKSHEET

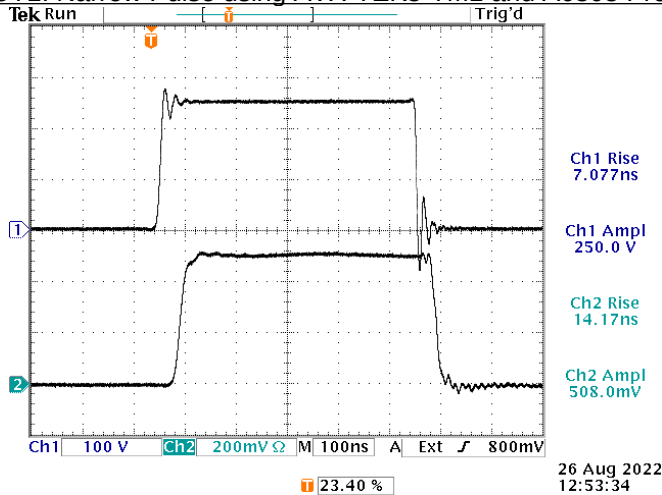
Model: AVR-3-PW-TEK3-B-P
Type: High-Speed Current Probe Test System
S.N.: 14268
Date: August 26, 2022

OUT1: Narrow Pulse into a 50Ω Test Load



Output of "OUT1" connector, terminated into an external 50 Ohm test load. Viewed with TDS3052 scope. 100V/div, 100 ns/div. 10 Hz.

OUT1: Narrow Pulse using AVX-TEK3-TM1 and A6303 Probe



Top: +250V voltage waveform (measured at clamping cable).
Bottom: Output of A6303 probe, viewed with TDS3052 scope.
The A6303 probe is clamped to the shorting cable.

a) Output Signal Amplitude (to 50Ω):
OUT1: up to +250V (+5A max.)
OUT2: up to +50 V (+1A max.)

b) Pulse Width:
OUT1: 250 ns to 250 us
OUT2: 50 ns to 200 ns

c) Rise Time (20-80%):
OUT1: < 10 ns
OUT2: < 0.5 ns

d) Fall Time (80-20%):
OUT1: < 10 ns
OUT2: < 0.5 ns

e) PRF: 0 - 10 kHz

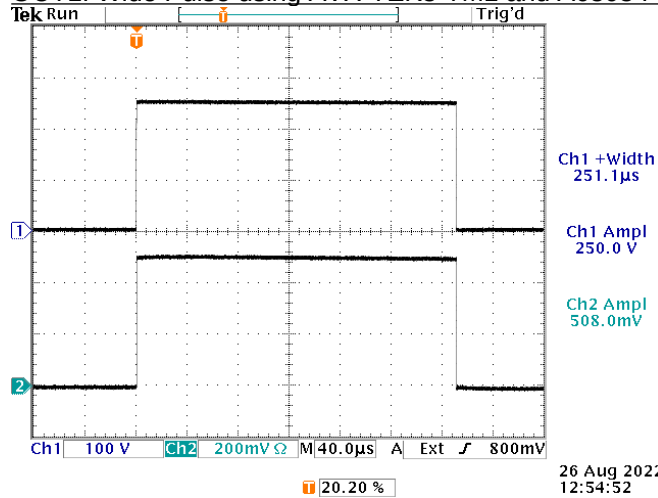
f) Jitter, Stability: OK

g) Prime Power: 100-240V AC, 50-60 Hz.

The current probes used in obtaining these waveforms are not calibrated, and are for examples purposes only. The amplitudes from the probes may be out of tolerance.

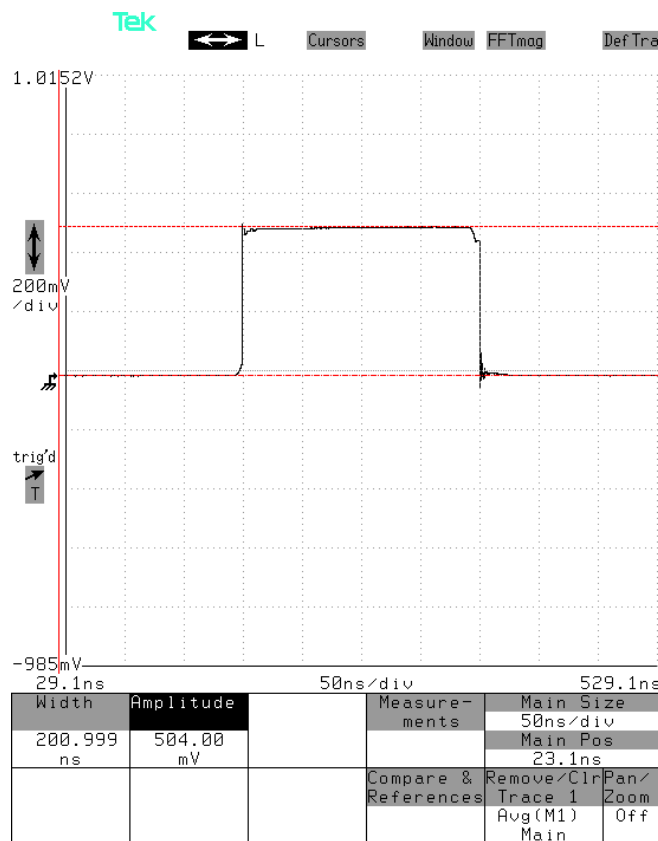
All rise/fall references levels: 20%, 80%.

OUT1: Wide Pulse using AVX-TEK3-TM1 and A6303 Probe

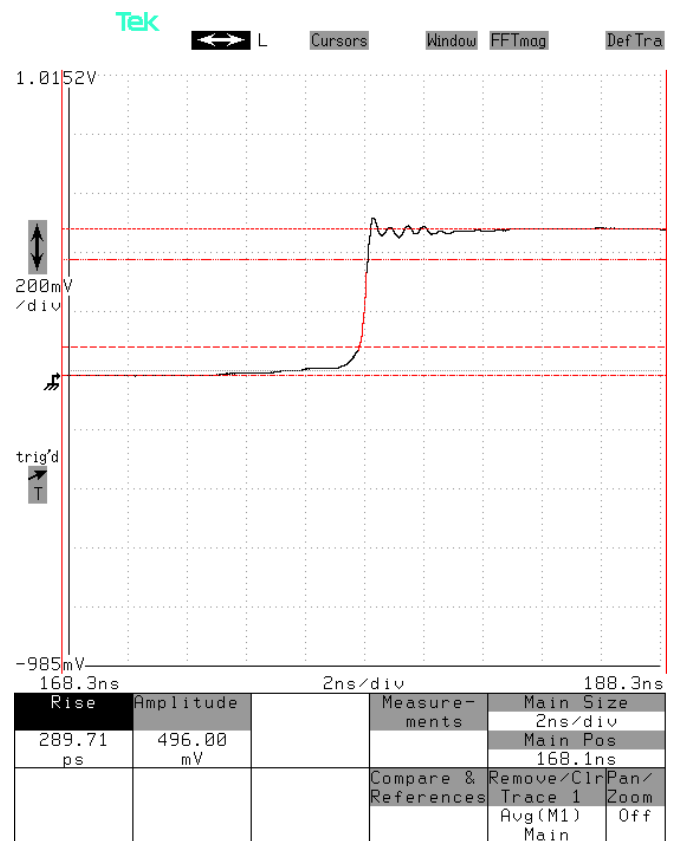


Top: +250V voltage waveform (measured at clamping cable). Bottom: Output of A6303 probe, viewed with TDS3052 scope. The A6303 probe is clamped to the shorting cable.

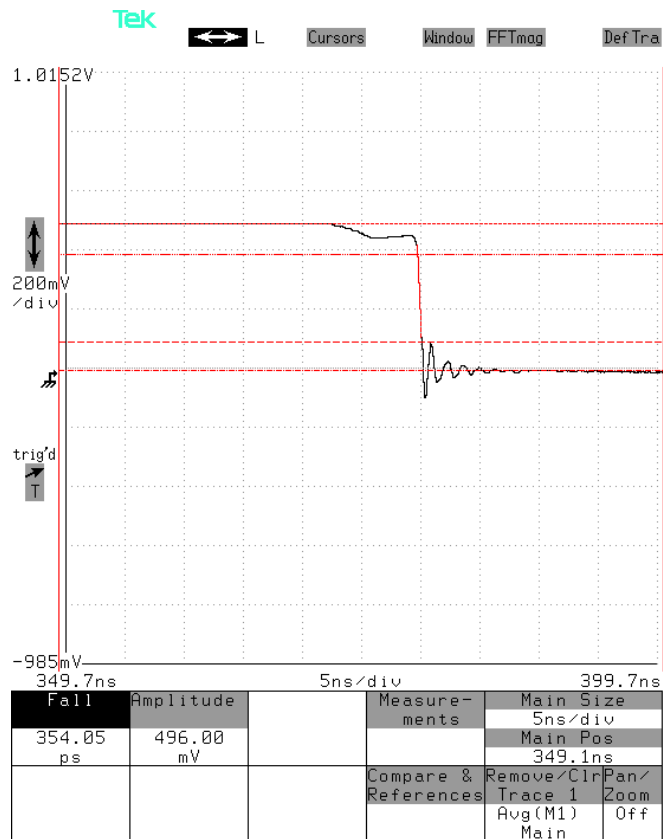
OUT2: 200 ns Pulse into a 50Ω Test Load



20 V/div (200 mV/div x 40 dB), 50 ns/div. "OUT2" into a sampling oscilloscope.

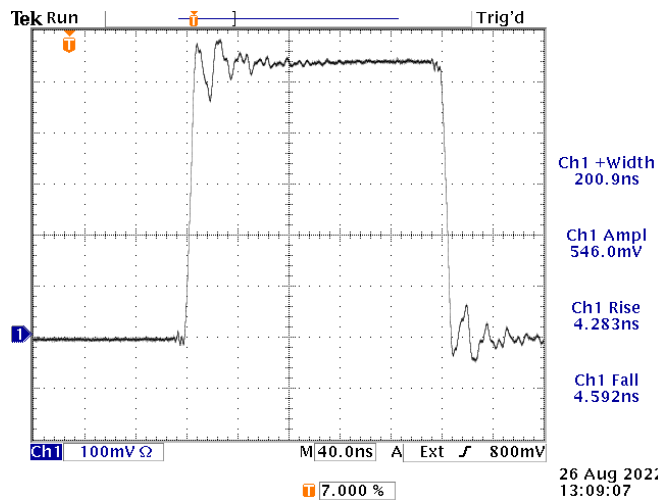


Same, but scaled at 2 ns / div to show rising edge.



Same, but scaled at 5 ns / div to show falling edge.

OUT2: 200 ns Pulse using AVX-TEK3-TM2 and P6042 Probe



Output of P6042 probe, viewed with TDS3052 scope. The P6042 probe is clamped to the shorting cable.